Claims

- 1. (currently amended) A magnetic thin film layer structure comprising:
 - a layer of RuAl;
 - a layer of NiAIB epitaxially deposited on the layer of RuAI; and
 - a ferromagnetic layer structure deposited after the layer of NiAlB.
- 2. (original) The magnetic thin film layer structure of claim 1 wherein the NiAlB has approximately from 2 to 5 atomic percent boron with the remainder being generally divided between nickel and aluminum.
- 3. (original) The magnetic thin film layer structure of claim 2 wherein NiAlB has approximately 50 atomic percent nickel, 48 atomic percent aluminum and 2 atomic percent boron.
- 4. (original) The magnetic thin film layer structure of claim 1 further comprising a substrate and a pre-seed layer of CrTi deposited on the substrate prior to the layer of RuAl.
- 5. (currently amended) The magnetic thin film layer structure of <u>claim 5</u> claim 1 wherein the substrate is circumferentially textured glass.
- 6. (original) The magnetic thin film layer structure of claim 1 further comprising an underlayer of CrTi deposited on the layer of NiAIB.
- 7. (currently amended) The magnetic thin film layer structure of claim 1 wherein the ferromagnetic layer structure further comprises comprising a magnetic layer stack including a layer of CoCr and a layer of CoPtCrB separated by a spacer layer.

- 8. (original) The magnetic thin film layer structure of claim 7 wherein the spacer layer is ruthenium.
- 9. (currently amended) A magnetic thin film disk comprising:

an amorphous or nanocrystalline pre-seed layer;

a seed layer of RuAl with a B2 crystallographic structure deposited on the pre-seed layer;

a seed layer of NiAlB deposited with a B2 crystallographic structure deposited on the layer of RuAl, the NiAlB having approximately from 2 to 5 atomic percent boron with the remainder being generally divided between nickel and aluminum; and

a at least one ferromagnetic layer structure above the layer of NiAlB.

- 10. (cancelled) The magnetic thin film disk of claim 9 wherein the NiAlB has approximately from 2 to 5 atomic percent boron with the remainder being generally divided between nickel and aluminum.
- 11. (currently amended) The magnetic thin film disk of claim 10 wherein the seed layer of NiAIB has approximately 2 at.% boron.
- 12. (original) The magnetic thin film disk of claim 9 further comprising a substrate and wherein the pre-seed layer is CrTi deposited on the substrate.
- 13. (currently amended) The magnetic thin film disk of claim 9 further comprising an underlayer of CrTi deposited on the layer of NiAlB prior to the ferromagnetic layer <u>structure</u>.
- 14. (currently amended) The magnetic thin film disk of claim 9 wherein the ferromagnetic layer <u>structure includes</u> is CoPtCrB and is preceded by a spacer layer and a layer of CoCr forming a magnetic layer stack.

- 15. (currently amended) A magnetic disk drive comprising: a magnetic transducer including a read head and a write head; a suspension supporting the magnetic transducer over a magnetic disk; and
- the magnetic disk including a dual seed layer <u>comprising a layer RuAl</u> <u>followed by a layer of NiAlB epitaxially deposited onto the layer of RuAl</u> ef <u>RuAl/NiAlB</u>.
- 16. (currently amended) The magnetic disk drive of claim 15 wherein the <u>layer of</u> NiAIB has approximately from 2 to 5 atomic percent boron with the remainder being generally divided between nickel and aluminum.
- 17. (currently amended) The magnetic disk drive of claim 16 wherein the layer of NiAlB has approximately 50 atomic percent nickel, 48 atomic percent aluminum and 2 atomic percent boron.
- 18. (original) The magnetic disk drive of claim 15 wherein the magnetic disk further comprises a circumferentially textured substrate and the magnetic disk has an Mrt orientation ratio greater than one.
- 19. (original) The magnetic disk drive of claim 15 wherein the magnetic disk further comprises an underlayer of CrTi deposited on the layer of NiAlB.
- 20. (currently amended) The magnetic disk drive of claim 15 wherein the magnetic disk further comprises a magnetic layer stack <u>deposited after the layer of NiAlB</u> including a layer of CoCr and a layer CoPtCrB separated by a spacer layer.